

<b>Notice of References Cited</b>	Application/Control No.		Applicant(s)/Patent Under Reexamination	
	09/832,933		WU ET AL.	
	Examiner		Art Unit	Page 1 of 1
Thomas H. Stevens		2123		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,761,481	06-1998	Kadoch et al.	703/2
*	B	US-6,363,515	03-2002	Rajgopal et al.	716/5
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chen et al., "A Unified Compact Scalable Model for Hot Carrier Reliability Simulation" IEEE 1999 pg.243-248.
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.